Shunri Oda

List of Publications by Year in Descending Order

Source: https://exaly.com/author-pdf/6228171/shunri-oda-publications-by-year.pdf

Version: 2024-04-20

This document has been generated based on the publications and citations recorded by exaly.com. For the latest version of this publication list, visit the link given above.

The third column is the impact factor (IF) of the journal, and the fourth column is the number of citations of the article.

4,380 293 31 51 h-index g-index citations papers 4,966 5.27 357 2.7 avg, IF L-index ext. citations ext. papers

#	Paper	IF	Citations
293	Synthesis and characterization of Ge-core/a-Si-shell nanowires with conformal shell thickness deposited after gold removal for high-mobility p-channel field-effect transistors. <i>Nanoscale Advances</i> , 2020 , 2, 1465-1472	5.1	1
292	Transfer printing of gate dielectric and carrier doping with poly(vinyl-alcohol) coating to fabricate top-gate molybdenum disulfide field-effect transistors. <i>Japanese Journal of Applied Physics</i> , 2020 , 59, 120903	1.4	1
291	Temperature dependence of hole transport properties through physically defined silicon quantum dots. <i>Applied Physics Letters</i> , 2020 , 117, 094001	3.4	1
290	Physically defined silicon triple quantum dots charged with few electrons in metal-oxide-semiconductor structures. <i>Applied Physics Letters</i> , 2020 , 117, 074001	3.4	5
289	Physically defined triple quantum dot systems in silicon on insulator. <i>Applied Physics Letters</i> , 2019 , 114, 073104	3.4	6
288	Comparison of picosecond electron dynamics in isolated and clustered Si quantum dots deposited on a semiconductor surface. <i>Applied Physics Letters</i> , 2019 , 115, 053105	3.4	1
287	Transfer printing of Al2O3 gate dielectric for fabrication of top-gate MoS2 FET. <i>Applied Physics Express</i> , 2019 , 12, 026501	2.4	2
286	A quantum-dot spin qubit with coherence limited by charge noise and fidelity higher than 99.9. <i>Nature Nanotechnology</i> , 2018 , 13, 102-106	28.7	340
285	An electronic synaptic device based on HfOTiO bilayer structure memristor with self-compliance and deep-RESET characteristics. <i>Nanotechnology</i> , 2018 , 29, 415205	3.4	18
284	Characteristics of multilevel storage and switching dynamics in resistive switching cell of Al2O3/HfO2/Al2O3 sandwich structure. <i>Journal Physics D: Applied Physics</i> , 2018 , 51, 025102	3	14
283	Optimized electrical control of a Si/SiGe spin qubit in the presence of an induced frequency shift. <i>Npj Quantum Information</i> , 2018 , 4,	8.6	13
282	Control of threshold voltage by gate metal electrode in molybdenum disulfide field-effect transistors. <i>Applied Physics Letters</i> , 2017 , 110, 133507	3.4	11
281	Charge sensing and spin-related transport property of p-channel silicon quantum dots. <i>Japanese Journal of Applied Physics</i> , 2017 , 56, 04CK07	1.4	11
280	Transfer printing of nanostructured membrane with elastomeric stamp and its application to TMDC-based field-effect transistors 2017 ,		1
279	Observation and coherent control of interface-induced electronic resonances in a field-effect[transistor. <i>Nature Materials</i> , 2017 , 16, 208-213	27	7
278	Use of self-assembled monolayers for selective metal removal and ultrathin gate dielectrics in MoS2 field-effect transistors. <i>Japanese Journal of Applied Physics</i> , 2017 , 56, 04CP10	1.4	2
277	A flexible terahertz scanner for omnidirectional imaging 2017 ,		1

(2015-2016)

276	Undoped and catalyst-free germanium nanowires for high-performance p-type enhancement-mode field-effect transistors. <i>Journal of Materials Chemistry C</i> , 2016 , 4, 5102-5108	7.1	12
275	A flexible and wearable terahertz scanner. <i>Nature Photonics</i> , 2016 , 10, 809-813	33.9	106
274	Adhesion lithography to fabricate MoS2 FETs with self-assembled monolayer-based gate dielectrics 2016 ,		3
273	Electron transport in physically-defined double quantum dots on a highly doped silicon-on-insulator substrate. <i>Applied Physics Letters</i> , 2016 , 109, 113109	3.4	3
272	Utilizing self-assembled-monolayer-based gate dielectrics to fabricate molybdenum disulfide field-effect transistors. <i>Applied Physics Letters</i> , 2016 , 108, 041605	3.4	24
271	Deionization of Dopants in Silicon Nanofilms Even with Donor Concentration of Greater than 10(19) cm(-3). <i>Nano Letters</i> , 2016 , 16, 1143-9	11.5	2
270	Scaling dependence of memory windows and different carrier charging behaviors in Si nanocrystal nonvolatile memory devices. <i>Chinese Physics B</i> , 2016 , 25, 097304	1.2	
269	Experimental Study on Deformation Potential (\${D}_{{{ac}}}\$) in MOSFETs: Demonstration of Increased \${D}_{{{ac}}}\$ at MOS Interfaces and Its Impact on Electron Mobility. <i>IEEE Journal of the Electron Devices Society</i> , 2016 , 4, 278-285	2.3	5
268	Effect of gold migration on the morphology of germanium nanowires grown by a two-step growth method with temperature modulation. <i>Japanese Journal of Applied Physics</i> , 2016 , 55, 085002	1.4	
267	A fault-tolerant addressable spin qubit in a natural silicon quantum dot. <i>Science Advances</i> , 2016 , 2, e16	00:69:4	120
267 266	A fault-tolerant addressable spin qubit in a natural silicon quantum dot. <i>Science Advances</i> , 2016 , 2, e16 Electron transport through a single nanocrystalline silicon quantum dot between nanogap electrodes. <i>Applied Physics Letters</i> , 2016 , 109, 213102	3.4	120
,	Electron transport through a single nanocrystalline silicon quantum dot between nanogap		
266	Electron transport through a single nanocrystalline silicon quantum dot between nanogap electrodes. <i>Applied Physics Letters</i> , 2016 , 109, 213102		1
266 265	Electron transport through a single nanocrystalline silicon quantum dot between nanogap electrodes. <i>Applied Physics Letters</i> , 2016 , 109, 213102 Coupled quantum dots on SOI as highly integrated Si qubits 2016 ,		3
266 265 264	Electron transport through a single nanocrystalline silicon quantum dot between nanogap electrodes. <i>Applied Physics Letters</i> , 2016 , 109, 213102 Coupled quantum dots on SOI as highly integrated Si qubits 2016 , Thickness dependence of terahertz plasmonic antenna 2016 , Split-joint bull@ eye structure with aperture optimization for multi-frequency terahertz plasmonic		1 3 1
266 265 264 263	Electron transport through a single nanocrystalline silicon quantum dot between nanogap electrodes. <i>Applied Physics Letters</i> , 2016 , 109, 213102 Coupled quantum dots on SOI as highly integrated Si qubits 2016 , Thickness dependence of terahertz plasmonic antenna 2016 , Split-joint bull@ eye structure with aperture optimization for multi-frequency terahertz plasmonic antennas 2016 ,		1 3 1
266 265 264 263 262	Electron transport through a single nanocrystalline silicon quantum dot between nanogap electrodes. <i>Applied Physics Letters</i> , 2016 , 109, 213102 Coupled quantum dots on SOI as highly integrated Si qubits 2016 , Thickness dependence of terahertz plasmonic antenna 2016 , Split-joint bull@ eye structure with aperture optimization for multi-frequency terahertz plasmonic antennas 2016 , Mechanism of carbon nanotubes terahertz detectors based on photothermoelectric effect 2016 , Back-action-induced excitation of electrons in a silicon quantum dot with a single-electron	3.4	1 3 1 1

258	Lithographically defined few-electron silicon quantum dots based on a silicon-on-insulator substrate. <i>Applied Physics Letters</i> , 2015 , 106, 083111	3.4	18
257	Ge/Si core/shell nanowires with controlled low temperature grown Si shell thickness. <i>Physica Status Solidi (A) Applications and Materials Science</i> , 2015 , 212, 1578-1581	1.6	1
256	Proposal for fast-response radial Schottky junction photodetectors based on silicon nanowires. <i>Japanese Journal of Applied Physics</i> , 2015 , 54, 034301	1.4	O
255	Formation of three-dimensionally integrated nanocrystalline silicon particles by dip-coating method. <i>Japanese Journal of Applied Physics</i> , 2015 , 54, 105001	1.4	О
254	Visualization of Ultrafast Electron Dynamics Using Time-Resolved Photoemission Electron Microscopy. <i>Springer Proceedings in Physics</i> , 2015 , 337-340	0.2	1
253	Coupled Si Quantum Dots for Spin-Based Qubits 2015 , 231-253		
252	Charge noise analysis of metal oxide semiconductor dual-gate Si/SiGe quantum point contacts. <i>Journal of Applied Physics</i> , 2014 , 115, 203709	2.5	1
251	In situ monitoring of silicon nanocrystal formation with pulsed SiH4supply by optical emission spectroscopy of Ar plasma. <i>Japanese Journal of Applied Physics</i> , 2014 , 53, 116102	1.4	4
250	GHz photon-activated hopping between localized states in a silicon quantum dot. <i>New Journal of Physics</i> , 2014 , 16, 013016	2.9	2
249	Fabrication and characterization of p-channel Si double quantum dots. <i>Applied Physics Letters</i> , 2014 , 105, 113110	3.4	8
248	Experimental study on SET/RESET conditions for graphene resistive random access memory. Japanese Journal of Applied Physics, 2014 , 53, 04EN02	1.4	2
247	Surface passivation of germanium nanowires using Al2O3and HfO2deposited via atomic layer deposition technique. <i>Japanese Journal of Applied Physics</i> , 2014 , 53, 06JG04	1.4	8
246	Optimization and Tunnel Junction Parameters Extraction of Electrostatically Defined Silicon Double Quantum Dots Structure. <i>Japanese Journal of Applied Physics</i> , 2013 , 52, 081301	1.4	
245	Microscopic study of germanium nanowires grown via gold-catalyzed chemical vapor deposition below the eutectic temperature. <i>Journal of Crystal Growth</i> , 2013 , 384, 77-81	1.6	3
244	GaAs/AlGaAs field-effect transistor for tunable terahertz detection and spectroscopy with built-in signal modulation. <i>Applied Physics Letters</i> , 2013 , 102, 122102	3.4	10
243	Dual Function of Single Electron Transistor Coupled with Double Quantum Dot: Gating and Charge Sensing. <i>Japanese Journal of Applied Physics</i> , 2013 , 52, 04CJ01	1.4	13
242	Experimental Study of Two-Terminal Resistive Random Access Memory Realized in Mono- and Multilayer Exfoliated Graphene Nanoribbons. <i>Japanese Journal of Applied Physics</i> , 2013 , 52, 04CN05	1.4	4
241	Methodology for Evaluating Operation Temperatures of Fin-Type Field-Effect Transistors Connected by Interconnect Wires. <i>Japanese Journal of Applied Physics</i> , 2013 , 52, 064203	1.4	9

(2011-2013)

240	Self-Heating Effects and Analog Performance Optimization of Fin-Type Field-Effect Transistors. Japanese Journal of Applied Physics, 2013 , 52, 04CC03	1.4	13	
239	Channel Length Scaling and Surface Nitridation of Silicon Nanocrystals for High-Performance Electron Devices. <i>Japanese Journal of Applied Physics</i> , 2013 , 52, 04CH08	1.4	O	
238	Characterization and suppression of low-frequency noise in Si/SiGe quantum point contacts and quantum dots. <i>Applied Physics Letters</i> , 2013 , 102, 123113	3.4	21	
237	Impact of Deformation Potential Increase at Si/SiO2Interfaces on Stress-Induced Electron Mobility Enhancement in Metal®xideBemiconductor Field-Effect Transistors. <i>Japanese Journal of Applied Physics</i> , 2013 , 52, 04CC12	1.4	4	
236	Conduction Bottleneck in Silicon Nanochain Single Electron Transistors Operating at Room Temperature. <i>Japanese Journal of Applied Physics</i> , 2012 , 51, 025202	1.4	2	
235	High ON/OFF ratio and multimode transport in silicon nanochains field effect transistors. <i>Applied Physics Letters</i> , 2012 , 100, 113108	3.4	5	
234	Experimental study of self-heating effect (SHE) in SOI MOSFETs: Accurate understanding of temperatures during AC conductance measurement, proposals of 2Imethod and modified pulsed IV 2012 ,		20	
233	A Multi-Purpose Electrostatically Defined Silicon Quantum Dot Structure. <i>Japanese Journal of Applied Physics</i> , 2012 , 51, 02BJ10	1.4	1	
232	Photoluminescence of Nanocrystalline Silicon Quantum Dots with Various Sizes and Various Phosphorus Doping Concentrations Prepared by Very High Frequency Plasma. <i>Japanese Journal of Applied Physics</i> , 2012 , 51, 115202	1.4	3	
231	Temperature Evolution of Spin-Polarized Electron Tunneling in Silicon Nanowire P ermalloy Lateral Spin Valve System. <i>Applied Physics Express</i> , 2012 , 5, 045001	2.4	5	
230	Key capacitive parameters for designing single-electron transistor charge sensors. <i>Journal of Applied Physics</i> , 2012 , 111, 093715	2.5	11	
229	Magnetic field dependence of Pauli spin blockade: A window into the sources of spin relaxation in silicon quantum dots. <i>Physical Review B</i> , 2012 , 86,	3.3	40	
228	Localization effects in the tunnel barriers of phosphorus-doped silicon quantum dots. <i>AIP Advances</i> , 2012 , 2, 022114	1.5	4	
227	Conduction Bottleneck in Silicon Nanochain Single Electron Transistors Operating at Room Temperature. <i>Japanese Journal of Applied Physics</i> , 2012 , 51, 025202	1.4	6	
226	Photoluminescence of Nanocrystalline Silicon Quantum Dots with Various Sizes and Various Phosphorus Doping Concentrations Prepared by Very High Frequency Plasma. <i>Japanese Journal of Applied Physics</i> , 2012 , 51, 115202	1.4	8	
225	A Multi-Purpose Electrostatically Defined Silicon Quantum Dot Structure. <i>Japanese Journal of Applied Physics</i> , 2012 , 51, 02BJ10	1.4		
224	Germanium nanowires with 3-nm-diameter prepared by low temperature vapour-liquid-solid chemical vapour deposition. <i>Journal of Nanoscience and Nanotechnology</i> , 2011 , 11, 8163-8	1.3	11	
223	Experimental evidence of increased deformation potential at MOS interface and its impact on characteristics of ETSOI FETs 2011 ,		8	

222	Temperature insensitive conductance detection with surface-functionalised silicon nanowire sensors. <i>Microelectronic Engineering</i> , 2011 , 88, 1753-1756	2.5	1
221	Growth of GeBi nanowire heterostructures via chemical vapor deposition. <i>Thin Solid Films</i> , 2011 , 519, 4174-4176	2.2	7
220	Size Reduction and Phosphorus Doping of Silicon Nanocrystals Prepared by a Very High Frequency Plasma Deposition System. <i>Japanese Journal of Applied Physics</i> , 2011 , 50, 025002	1.4	8
219	Study on Device Parameters of Carbon Nanotube Field Electron Transistors to Realize Steep Subthreshold Slope of Less than 60 mV/Decade. <i>Japanese Journal of Applied Physics</i> , 2011 , 50, 04DN01	1.4	7
218	Removal of Surface Oxide Layer from Silicon Nanocrystals by Hydrogen Fluoride Vapor Etching. Japanese Journal of Applied Physics, 2011 , 50, 115002	1.4	5
217	Experimental Study on Electron Mobility in Accumulation-Mode Silicon-on-Insulator Metall Dxide Bemiconductor Field-Effect Transistors. <i>Japanese Journal of Applied Physics</i> , 2011 , 50, 09410	o 1·4	5
216	Simulation Study of Charge Modulation in Coupled Quantum Dots in Silicon. <i>Japanese Journal of Applied Physics</i> , 2011 , 50, 04DJ05	1.4	2
215	Numerical simulation study of electrostatically defined silicon double quantum dot device. <i>Journal of Applied Physics</i> , 2011 , 110, 054511	2.5	3
214	Tip-enhanced Raman mapping of a single Ge nanowire. <i>Applied Physics Letters</i> , 2011 , 99, 053112	3.4	30
213	Electron mobility enhancement in nanoscale silicon-on-insulator diffusion layers with high doping concentration of greater than 1 🛘 018 cm and silicon-on-insulator thickness of less than 10 nm. <i>Journal of Applied Physics</i> , 2011 , 110, 034502	2.5	8
212	Detection of variable tunneling rates in silicon quantum dots. <i>Applied Physics Letters</i> , 2011 , 98, 133506	3.4	4
211	Experimental study on subband structures and hole transport in (110) Si p-type metal-oxide-semiconductor field-effect transistors under high magnetic field. <i>Journal of Applied Physics</i> , 2011 , 109, 034505	2.5	3
21 0	Demonstration of spin valve effects in silicon nanowires. <i>Journal of Applied Physics</i> , 2011 , 109, 07C508	2.5	10
209	Thermal-aware device design of nanoscale bulk/SOI FinFETs: Suppression of operation temperature and its variability 2011 ,		25
208	Growth of Narrow and Straight Germanium Nanowires by VaporliquidBolid Chemical Vapor Deposition. <i>Japanese Journal of Applied Physics</i> , 2011 , 50, 105002	1.4	3
207	Size Reduction and Phosphorus Doping of Silicon Nanocrystals Prepared by a Very High Frequency Plasma Deposition System. <i>Japanese Journal of Applied Physics</i> , 2011 , 50, 025002	1.4	5
206	Growth of Narrow and Straight Germanium Nanowires by VaporliquidBolid Chemical Vapor Deposition. <i>Japanese Journal of Applied Physics</i> , 2011 , 50, 105002	1.4	10
205	Removal of Surface Oxide Layer from Silicon Nanocrystals by Hydrogen Fluoride Vapor Etching. Japanese Journal of Applied Physics, 2011 , 50, 115002	1.4	6

(2009-2011)

204	Simulation Study of Charge Modulation in Coupled Quantum Dots in Silicon. <i>Japanese Journal of Applied Physics</i> , 2011 , 50, 04DJ05	1.4	
203	Design of New Logic Architectures Utilizing Optimized Suspended-Gate Single-Electron Transistors. <i>IEEE Nanotechnology Magazine</i> , 2010 , 9, 504-512	2.6	1
202	Current fluctuations in three-dimensionally stacked Si nanocrystals thin films. <i>Applied Physics Letters</i> , 2010 , 96, 092112	3.4	6
201	Vertical-coupled SiGe double quantum dots. <i>Electronics Letters</i> , 2010 , 46, 940	1.1	1
200	Experimental Observation of Enhanced Electron Phonon Interaction in Suspended Si Double Quantum Dots. <i>Japanese Journal of Applied Physics</i> , 2010 , 49, 045203	1.4	9
199	Suspended Quantum Dot Fabrication on a Heavily Doped Silicon Nanowire by Suppressing Unintentional Quantum Dot Formation. <i>Japanese Journal of Applied Physics</i> , 2010 , 49, 044001	1.4	3
198	Scaling Analysis of Nanoelectromechanical Memory Devices. <i>Japanese Journal of Applied Physics</i> , 2010 , 49, 044304	1.4	8
197	Silicon Nanocrystal Flash Memory 2010 , 395-444		2
196	Fabrication of Nanosilicon Ink and Two-Dimensional Array of Nanocrystalline Silicon Quantum Dots. Japanese Journal of Applied Physics, 2010 , 49, 125002	1.4	3
195	Anomalous electron mobility in extremely-thin SOI (ETSOI) diffusion layers with SOI thickness of less than 10 nm and high doping concentration of greater than 111018cmB 2010,		1
194	Position-Controllable Ge Nanowires Growth on Patterned Au Catalyst Substrate. <i>Applied Physics Express</i> , 2009 , 2, 015004	2.4	11
193	Control of Inter-Dot Electrostatic Coupling by a Side Gate in a Silicon Double Quantum Dot Operating at 4.5 K. <i>Applied Physics Express</i> , 2009 , 2, 095002	2.4	19
192	Single Hole Charging at Room Temperature of Ge Quantum Dots Grown on Si(001) by Molecular Beam Epitaxy. <i>Nanoscience and Nanotechnology Letters</i> , 2009 , 1, 82-86	0.8	2
191	Carrier transport by field enhanced thermal detrapping in Si nanocrystals thin films. <i>Journal of Applied Physics</i> , 2009 , 105, 124518	2.5	11
190	Electromechanical Simulation of Switching Characteristics for Nanoelectromechanical Memory. Japanese Journal of Applied Physics, 2009 , 48, 114502	1.4	5
189	Electron transport in surface oxidized Si nanocrystal ensembles with thin film transistor structure. <i>Journal of Applied Physics</i> , 2009 , 106, 044511	2.5	11
188	Spontaneous emission control of silicon nanocrystals by silicon three-dimensional photonic crystal structure fabricated by self-aligned two-directional electrochemical etching method. <i>Materials Chemistry and Physics</i> , 2009 , 116, 107-111	4.4	4
187	Electron transport through silicon serial triple quantum dots. <i>Solid-State Electronics</i> , 2009 , 53, 779-785	1.7	11

186	Design Optimization of NEMS Switches for Suspended-Gate Single-Electron Transistor Applications. <i>IEEE Nanotechnology Magazine</i> , 2009 , 8, 174-184	2.6	11
185	Electron Transport in Nanocrystalline Silicon. <i>Nanostructure Science and Technology</i> , 2009 , 197-221	0.9	2
184	Strongly coupled multiple-dot characteristics in dual recess structured silicon channel. <i>Journal of Applied Physics</i> , 2008 , 103, 043719	2.5	1
183	Impact of Key Circuit Parameters on Signal-to-Noise Ratio Characteristics for the Radio Frequency Single-Electron Transistors. <i>IEEE Nanotechnology Magazine</i> , 2008 , 7, 266-272	2.6	6
182	Enhanced tunnel conductance due to QCA cotunneling processes observed for silicon serial triple quantum dots 2008 ,		1
181	Transient response analysis of programming/readout characteristics for NEMS memory 2008,		2
180	Study of Single-Charge Polarization on a Pair of Charge Qubits Integrated Onto a Silicon Double Single-Electron Transistor Readout. <i>IEEE Nanotechnology Magazine</i> , 2008 , 7, 617-623	2.6	6
179	Controlled Ge nanowires growth on patterned Au catalyst substrate 2008,		1
178	Formation Mechanism of 100-nm-Scale Periodic Structures in Silicon Using Magnetic-Field-Assisted Anodization. <i>Japanese Journal of Applied Physics</i> , 2008 , 47, 7398-7402	1.4	16
177	VaporliquidBolid Growth of Small- and Uniform-Diameter Silicon Nanowires at Low Temperature from Si2H6. <i>Applied Physics Express</i> , 2008 , 1, 014003	2.4	16
176	Theoretical Study of Nonequilibrium Electron Transport and Charge Distribution in a Three-Site Quantum Wire. <i>Japanese Journal of Applied Physics</i> , 2008 , 47, 371-382	1.4	3
175	Synthesis of Assembled Nanocrystalline Si Dots Film by the Langmuir B lodgett Technique. <i>Japanese Journal of Applied Physics</i> , 2008 , 47, 3731-3734	1.4	6
174	Control of Electrostatic Coupling Observed for Silicon Double Quantum Dot Structures. <i>Japanese Journal of Applied Physics</i> , 2008 , 47, 4820-4826	1.4	17
173	Size-Dependent Structural Characterization of Silicon Nanowires. <i>Japanese Journal of Applied Physics</i> , 2008 , 47, 5053-5056	1.4	6
172	Visible Electroluminescence from Spherical-Shaped Silicon Nanocrystals. <i>Japanese Journal of Applied Physics</i> , 2008 , 47, 8137-8140	1.4	22
171	Silicon quantum dot devices 2008 ,		1
170	Voltage-limitation-free analytical single-electron transistor model incorporating the effects of spin-degenerate discrete energy states. <i>Journal of Applied Physics</i> , 2008 , 103, 054508	2.5	8
169	Room temperature single electron charging in single silicon nanochains. <i>Journal of Applied Physics</i> , 2008 , 103, 053705	2.5	26

(2006-2008)

168	Stochastic Coulomb blockade in coupled asymmetric silicon dots formed by pattern-dependent oxidation. <i>Applied Physics Letters</i> , 2008 , 92, 092110	3.4	7	
167	Impact of channel constrictions on the formation of multiple tunnel junctions in heavily doped silicon single electron transistors. <i>Applied Physics Letters</i> , 2008 , 93, 112107	3.4	7	
166	Field-dependant hopping conduction in silicon nanocrystal films. <i>Journal of Applied Physics</i> , 2008 , 104, 123710	2.5	9	
165	Silicon-on-insulator-based radio frequency single-electron transistors operating at temperatures above 4.2 K. <i>Nano Letters</i> , 2008 , 8, 4648-52	11.5	16	
164	Nonequilibrium transport properties for a three-site quantum wire model. <i>Physica Status Solidi C:</i> Current Topics in Solid State Physics, 2008 , 5, 56-60		1	
163	Single-electron tunnelling via quantum dot cavities built on a silicon suspension nanobridge. <i>Microelectronic Engineering</i> , 2008 , 85, 1410-1412	2.5	8	
162	Influence of the crystal orientation of substrate on low temperature synthesis of silicon nanowires from Si2H6. <i>Thin Solid Films</i> , 2008 , 517, 317-319	2.2	10	
161	Bottom-up approach to silicon nanoelectronics. <i>Microelectronics Journal</i> , 2008 , 39, 171-176	1.8	10	
160	Influence of nanocrystal size on the transport properties of Si nanocrystals. <i>Journal of Applied Physics</i> , 2008 , 104, 024518	2.5	25	
159	Charge storage and electron/light emission properties of silicon nanocrystals. <i>Physica E: Low-Dimensional Systems and Nanostructures</i> , 2007 , 38, 59-63	3	10	
158	Three-Dimensional Numerical Analysis of Switching Properties of High-Speed and Nonvolatile Nanoelectromechanical Memory. <i>IEEE Transactions on Electron Devices</i> , 2007 , 54, 1132-1139	2.9	13	
157	New Design Concept and Fabrication Process for Three-Dimensional Silicon Photonic Crystal Structures. <i>Japanese Journal of Applied Physics</i> , 2007 , 46, 633-637	1.4	8	
156	Integration of Tunnel-Coupled Double Nanocrystalline Silicon Quantum Dots with a Multiple-Gate Single-Electron Transistor. <i>Japanese Journal of Applied Physics</i> , 2007 , 46, 4386-4389	1.4	17	
155	3-D Design and Analysis of Functional NEMS-gate MOSFETs and SETs. <i>IEEE Nanotechnology Magazine</i> , 2007 , 6, 218-224	2.6	18	
154	Observation of interdot coupling phenomena in nanocrystalline silicon point-contact structures. <i>Current Applied Physics</i> , 2006 , 6, 536-540	2.6	1	
153	Observation and Analysis of Tunneling Properties of Single Spherical Nanocrystalline Silicon Quantum Dot. <i>Japanese Journal of Applied Physics</i> , 2006 , 45, 3638-3641	1.4	6	
152	Hopping conduction in size-controlled Si nanocrystals. <i>Journal of Applied Physics</i> , 2006 , 100, 014303	2.5	42	
151	Broadband variable chromatic dispersion in photonic-band electro-optic waveguide 2006 ,		1	

150	Nanoelectromechanical nonvolatile memory device incorporating nanocrystalline Si dots. <i>Journal of Applied Physics</i> , 2006 , 100, 094306	2.5	29
149	High-density assembly of nanocrystalline silicon quantum dots. Current Applied Physics, 2006, 6, 344-34	72.6	14
148	Inter-grain coupling effects on Coulomb oscillations in dual-gated nanocrystalline silicon point-contact transistors. <i>Thin Solid Films</i> , 2005 , 487, 255-259	2.2	
147	Atomic Force Microscope Current-Imaging Study for Current Density through Nanocrystalline Silicon Dots Embedded in SiO2. <i>Japanese Journal of Applied Physics</i> , 2005 , 44, L88-L91	1.4	5
146	Charge storage in nitrided nanocrystalline silicon dots. <i>Applied Physics Letters</i> , 2005 , 87, 173107	3.4	32
145	Charge injection and trapping in silicon nanocrystals. <i>Applied Physics Letters</i> , 2005 , 87, 182101	3.4	60
144	In situ real-time spectroscopic ellipsometry study of HfO2 thin films grown by using the pulsed-source metal-organic chemical-vapor deposition. <i>Journal of Applied Physics</i> , 2005 , 97, 023527	2.5	7
143	Probing electron charging in nanocrystalline Si dots using Kelvin probe force microscopy. <i>Applied Physics Letters</i> , 2004 , 85, 3262-3264	3.4	34
142	Quasiballistic Electron Emission from Planarized Nanocrystalline-Si Cold Cathode. <i>Materials Research Society Symposia Proceedings</i> , 2004 , 832, 341		
141	Formation of an Ordered Array of Nanocrystalline Si Dots by Using a Solution Droplet Evaporation Method. <i>Materials Research Society Symposia Proceedings</i> , 2004 , 818, 130		
140	Toward long-term retention-time single-electron-memory devices based on nitrided nanocrystalline silicon dots. <i>IEEE Nanotechnology Magazine</i> , 2004 , 3, 210-214	2.6	29
139	Pulsed-Source MOCVD of High-kDielectric Thin Films within situMonitoring by Spectroscopic Ellipsometry. <i>Japanese Journal of Applied Physics</i> , 2003 , 42, 1957-1961	1.4	6
138	NeoSilicon materials and silicon nanodevices. <i>Materials Science and Engineering B: Solid-State Materials for Advanced Technology</i> , 2003 , 101, 19-23	3.1	31
137	Photoluminescence of surface-nitrided nanocrystalline silicon dots. <i>Physica Status Solidi C: Current Topics in Solid State Physics</i> , 2003 , 1254-1257		5
136	Operation of nanocrystalline-silicon-based few-electron memory devices in the light of electron storage, ejection, and lifetime characteristics. <i>IEEE Nanotechnology Magazine</i> , 2003 , 2, 88-92	2.6	8
135	Conducting-tip atomic force microscopy for injection and probing of localized charges in silicon nanocrystals. <i>Applied Physics Letters</i> , 2003 , 83, 3788-3790	3.4	20
134	Electron trapping, storing, and emission in nanocrystalline Si dots by capacitanceNoltage and conductanceNoltage measurements. <i>Journal of Applied Physics</i> , 2003 , 93, 576-581	2.5	101
133	Quantum confinement energy in nanocrystalline silicon dots from high-frequency conductance measurement. <i>Journal of Applied Physics</i> , 2003 , 94, 7261-7265	2.5	54

132	Temperature and Frequency Dependencies of Charging and Discharging Properties in Mos Memory Based on Nanocrystalline Silicon Dot. <i>Materials Research Society Symposia Proceedings</i> , 2002 , 715, 1251	I	3	
131	Ballistic transport in silicon vertical transistors. <i>Journal of Applied Physics</i> , 2002 , 92, 1399-1405	2.5	15	
130	Nanocrystalline silicon electron emitter with a high efficiency enhanced by a planarization technique. <i>Journal of Applied Physics</i> , 2002 , 92, 2748-2757	2.5	89	
129	Evidence of storing and erasing of electrons in a nanocrystalline-Si based memory device at 77 K. Journal of Vacuum Science & Technology an Official Journal of the American Vacuum Society B, Microelectronics Processing and Phenomena, 2002 , 20, 1135		34	
128	Observation of Quantum Confinement Effects in Nanocrystalline Silicon Dot Floating Gate Single Electron Memory Devices. <i>Materials Research Society Symposia Proceedings</i> , 2002 , 737, 268			
127	Atomic Layer-by-Layer MOCVD of Complex Metal Oxides and In Situ Process Monitoring. <i>Chemical Vapor Deposition</i> , 2001 , 7, 7-18		15	
126	Emission lifetime of polarizable charge stored in nano-crystalline Si based single-electron memory. Journal of Applied Physics, 2001 , 90, 6402-6408	2.5	57	
125	Self-aligned double-gate single-electron transistor derived from 0.12-Th-scale electron-beam lithography. <i>Applied Physics Letters</i> , 2001 , 78, 2070-2072	3.4	14	
124	C-V and G-V Measurements Showing Single Electron Trapping in Nanocrystalline Silicon Dot Embedded in MOS Memory Structure. <i>Materials Research Society Symposia Proceedings</i> , 2001 , 686, 1		2	
123	Photoluminescence Study of Self-Limiting Oxidation in Nanocrystalline Silicon Quantum Dots. <i>Materials Research Society Symposia Proceedings</i> , 2001 , 664, 2061		12	
122	Nanocrystalline silicon quantum dots prepared by VHF plasma enhanced chemical vapor deposition. <i>European Physical Journal Special Topics</i> , 2001 , 11, Pr3-1065-Pr3-1071		5	
121	Charge Storage Mechanism in Nano-Crystalline Si Based Single-Electron Memories. <i>Materials Research Society Symposia Proceedings</i> , 2000 , 638, 1		3	
120	Retardation in the Oxidation Rate of Nanocrystalline Silicon Quantum Dots. <i>Materials Research Society Symposia Proceedings</i> , 2000 , 638, 1		8	
119	Fabrication and Characterization of Cold Electron Emitter Based on Nanocrystalline Silicon Dots. <i>Materials Research Society Symposia Proceedings</i> , 2000 , 638, 1		1	
118	Carrier conduction in a Si-nanocrystal-based single-electron transistor-II. Effect of drain bias. <i>Superlattices and Microstructures</i> , 2000 , 28, 189-198	2.8	8	
117	Carrier conduction in a Si-nanocrystal-based single-electron transistor-I. Effect of gate bias. <i>Superlattices and Microstructures</i> , 2000 , 28, 177-187	2.8	23	
116	Study of structural and optical properties of nanocrystalline silicon embedded in SiO2. <i>Thin Solid Films</i> , 2000 , 375, 137-141	2.2	40	
115	Electron-beam direct writing using RD2000N for fabrication of nanodevices. <i>Journal of Vacuum Science & Technology an Official Journal of the American Vacuum Society B, Microelectronics Processing and Phenomena</i> , 2000 , 18, 2857		7	

114	Room Temperature Single-Electron Narrow-Channel Memory with Silicon Nanodots Embedded in SiO2 Matrix. <i>Japanese Journal of Applied Physics</i> , 2000 , 39, L792-L795	1.4	21
113	Single-Electron Tunneling Devices Based on Silicon Quantum Dots Fabricated by Plasma Process. Japanese Journal of Applied Physics, 2000 , 39, 264-267	1.4	24
112	Electron Transport in Nanocrystalline Si Based Single Electron Transistors. <i>Japanese Journal of Applied Physics</i> , 2000 , 39, 4647-4650	1.4	69
111	Two-Gate Transistor for the Study of Si/SiO2Interface in Silicon-on-Insulator Nano-Channel and Nanocrystalline Si Memory Device. <i>Japanese Journal of Applied Physics</i> , 2000 , 39, 4637-4641	1.4	16
110	Structure Analysis of SrTiO3/BaTiO3Strained Superlattice Films Prepared by Atomic-Layer Metalorganic Chemical Vapor Deposition. <i>Japanese Journal of Applied Physics</i> , 2000 , 39, 4164-4167	1.4	3
109	Single Electron Memory Devices Based on Plasma-Derived Silicon Nanocrystals. <i>Japanese Journal of Applied Physics</i> , 2000 , 39, L855-L857	1.4	23
108	Electron transport in a single silicon quantum structure using a vertical silicon probe. <i>Journal of Applied Physics</i> , 2000 , 88, 4186	2.5	32
107	Conductance quantization in nanoscale vertical structure silicon field-effect transistors with a wrap gate. <i>Applied Physics Letters</i> , 2000 , 76, 2922-2924	3.4	15
106	Electrical Properties of SrTiO[sub 3]/BaTiO[sub 3] Strained Superlattice Films Prepared by Atomic Layer Metallorganic Chemical Vapor Deposition. <i>Journal of the Electrochemical Society</i> , 2000 , 147, 4615	3.9	14
105	?????tt????????. Electrochemistry, 2000 , 68, 1036-1037	1.2	
105	?????@???????. Electrochemistry, 2000, 68, 1036-1037 Reproducible Growth of Metalorganic Chemical Vapor Deposition Derived YBa2Cu3OxThin Films Using Ultrasonic Gas Concentration Analyzer. Japanese Journal of Applied Physics, 1999, 38, 4727-4732	1.2	8
	Reproducible Growth of Metalorganic Chemical Vapor Deposition Derived YBa2Cu3OxThin Films		8
104	Reproducible Growth of Metalorganic Chemical Vapor Deposition Derived YBa2Cu3OxThin Films Using Ultrasonic Gas Concentration Analyzer. <i>Japanese Journal of Applied Physics</i> , 1999 , 38, 4727-4732 Enhanced Dielectric Properties in SrTiO3/BaTiO3Strained Superlattice Structures Prepared by Atomic-Layer Metalorganic Chemical Vapor Deposition. <i>Japanese Journal of Applied Physics</i> , 1999 ,	1.4	
104	Reproducible Growth of Metalorganic Chemical Vapor Deposition Derived YBa2Cu3OxThin Films Using Ultrasonic Gas Concentration Analyzer. <i>Japanese Journal of Applied Physics</i> , 1999 , 38, 4727-4732 Enhanced Dielectric Properties in SrTiO3/BaTiO3Strained Superlattice Structures Prepared by Atomic-Layer Metalorganic Chemical Vapor Deposition. <i>Japanese Journal of Applied Physics</i> , 1999 , 38, 6817-6820 In Situ Growth Monitoring During Metalorganic Chemical Vapor Deposition of YBa 2Cu 3Ox Thin	1.4	31
104	Reproducible Growth of Metalorganic Chemical Vapor Deposition Derived YBa2Cu3OxThin Films Using Ultrasonic Gas Concentration Analyzer. <i>Japanese Journal of Applied Physics</i> , 1999 , 38, 4727-4732 Enhanced Dielectric Properties in SrTiO3/BaTiO3Strained Superlattice Structures Prepared by Atomic-Layer Metalorganic Chemical Vapor Deposition. <i>Japanese Journal of Applied Physics</i> , 1999 , 38, 6817-6820 In Situ Growth Monitoring During Metalorganic Chemical Vapor Deposition of YBa 2Cu 3Ox Thin Films by Spectroscopic Ellipsometry. <i>Japanese Journal of Applied Physics</i> , 1999 , 38, L632-L635 Silicon-based single-electron memory using a multiple-tunnel junction fabricated by electron-beam	1.4	31
104 103 102	Reproducible Growth of Metalorganic Chemical Vapor Deposition Derived YBa2Cu3OxThin Films Using Ultrasonic Gas Concentration Analyzer. <i>Japanese Journal of Applied Physics</i> , 1999 , 38, 4727-4732 Enhanced Dielectric Properties in SrTiO3/BaTiO3Strained Superlattice Structures Prepared by Atomic-Layer Metalorganic Chemical Vapor Deposition. <i>Japanese Journal of Applied Physics</i> , 1999 , 38, 6817-6820 In Situ Growth Monitoring During Metalorganic Chemical Vapor Deposition of YBa 2Cu 3Ox Thin Films by Spectroscopic Ellipsometry. <i>Japanese Journal of Applied Physics</i> , 1999 , 38, L632-L635 Silicon-based single-electron memory using a multiple-tunnel junction fabricated by electron-beam direct writing. <i>Applied Physics Letters</i> , 1999 , 75, 1422-1424 The nanostructuring of materials for device and sensor applications. <i>Engineering Science and</i>	1.4	31
104 103 102 101	Reproducible Growth of Metalorganic Chemical Vapor Deposition Derived YBa2Cu3OxThin Films Using Ultrasonic Gas Concentration Analyzer. <i>Japanese Journal of Applied Physics</i> , 1999, 38, 4727-4732 Enhanced Dielectric Properties in SrTiO3/BaTiO3Strained Superlattice Structures Prepared by Atomic-Layer Metalorganic Chemical Vapor Deposition. <i>Japanese Journal of Applied Physics</i> , 1999, 38, 6817-6820 In Situ Growth Monitoring During Metalorganic Chemical Vapor Deposition of YBa 2Cu 3Ox Thin Films by Spectroscopic Ellipsometry. <i>Japanese Journal of Applied Physics</i> , 1999, 38, L632-L635 Silicon-based single-electron memory using a multiple-tunnel junction fabricated by electron-beam direct writing. <i>Applied Physics Letters</i> , 1999, 75, 1422-1424 The nanostructuring of materials for device and sensor applications. <i>Engineering Science and Education Journal</i> , 1999, 8, 281-285 Nanostructured materials and devices for sensor and electronic applications. <i>Power Engineering</i>	1.4	31 2 16

Two-dimensional dynamical triangulation using the grand-canonical ensemble. Nuclear Physics, 96 Section B, Proceedings Supplements, 1998, 63, 733-735 Electric Properties of Coplanar High-TCSuperconducting Field-Effect Devices. Japanese Journal of 18 95 1.4 Applied Physics, 1998, 37, 492-495 Observation of the single electron charging effect in nanocrystalline silicon at room temperature 94 27 3.4 using atomic force microscopy. Applied Physics Letters, 1998, 72, 1089-1091 Grand-Canonical Simulation of Two-Dimensional Simplicial Gravity 1998, 99, 875-884 93 Fabrication of Nanocrystalline Silicon with Small Spread of Particle Size by Pulsed Gas Plasma. 100 92 1.4 Japanese Journal of Applied Physics, 1997, 36, 4031-4034 Fabrication and Electrical Characteristics of Single Electron Tunneling Devices Based on Si Quantum 91 1.4 41 Dots Prepared by Plasma Processing. Japanese Journal of Applied Physics, 1997, 36, 4038-4041 Photoluminescence mechanism in surface-oxidized silicon nanocrystals. Physical Review B, 1997, 55, R737,5-R737,84 90 Junction formation in YBaCuO thin films by scanning probe technologies. Journal of Low 89 1.3 Temperature Physics, 1997, 106, 423-432 Proposal of coplanar-type high-Tc superconducting field-effect devices. Physica C: Superconductivity 88 1.3 3 and Its Applications, 1997, 282-287, 2495-2496 Anomalous current-voltage characteristics along the c-axis in YBaCuO thin films prepared by 87 1.3 MOCVD and AFM lithography. Physica C: Superconductivity and Its Applications, 1997, 293, 244-248 Atomic layer-by-layer epitaxy of oxide superconductors by MOCVD. Applied Surface Science, 1997, 86 6.7 12 112, 30-37 Preparation of nanocrystalline silicon quantum dot structure by a digital plasma process. Advances 85 14.3 15 in Colloid and Interface Science, 1997, 71-72, 31-47 Preparation of nanocrystalline silicon quantum dot structure by a digital plasma process. Advances 84 14.3 9 in Colloid and Interface Science, 1997, 71-72, 31-47 Preferential Nucleation of Nanocrystalline Silicon along Microsteps. Japanese Journal of Applied 83 1.4 Physics, 1996, 35, 1325-1328 Nanocrystalline silicon formation in a SiH4 plasma cell. Journal of Non-Crystalline Solids, 1996, 82 3.9 33 198-200, 875-878 Grain-Size Control of Nanocrystalline Silicon by Pulsed Gas Plasma Process. Materials Research 81 5 Society Symposia Proceedings, 1996, 452, 749 Preparation of thin films of YBa2Cu3Ox with a smooth surface by atomic layer MOCVD. Materials 80 2 3.1 Science and Engineering B: Solid-State Materials for Advanced Technology, 1996, 41, 87-92 . IEEE Transactions on Applied Superconductivity, 1995, 5, 1801-1804 1.8 79

78	Computer Simulation and Measurement of Capacitance-Voltage Characteristics in Quantum Wire Devices of Trench-Oxide MOS Structure. <i>Japanese Journal of Applied Physics</i> , 1995 , 34, 874-877	1.4	3
77	Fabrication of Nanocrystalline Si by SiH4 Plasma Cell. <i>Materials Research Society Symposia Proceedings</i> , 1995 , 377, 51		11
76	Critical Current Density of YBCO Ultra Thin Films Prepared by Atomic Layer MOCVD 1995 , 979-982		1
75	Atomic Layer-by-Layer MOCVD of Oxide Superconductors. <i>European Physical Journal Special Topics</i> , 1995 , 05, C5-379-C5-390		3
74	Selective Etching of Hydrogenated Amorphous Silicon by Hydrogen Plasma. <i>Japanese Journal of Applied Physics</i> , 1994 , 33, 4442-4445	1.4	39
73	Superconducting Properties of Ultrathin Films of \$bf YBa_{2}Cu_{3}O_{ninmbi{x}}\$ Prepared by Metalorganic Chemical Vapor Deposition at \$bf 500^{circ}C\$. <i>Japanese Journal of Applied Physics</i> , 1994 , 33, L312-L314	1.4	10
72	Preparation of Y-doped SrCuO2 infinite layer films by MOCVD. <i>Physica C: Superconductivity and Its Applications</i> , 1994 , 235-240, 979-980	1.3	
71	Staircase-like structures in in situ optical reflectance measurement as an evidence for two-dimensional crystal growth in layer-by-layer chemical vapor deposition of YBa2Cu3Ox. <i>Applied Surface Science</i> , 1994 , 75, 259-262	6.7	7
70	Atomic layer controlled metalorganic chemical vapor deposition of superconducting YBa2Cu3Ox films. <i>Journal of Crystal Growth</i> , 1994 , 145, 232-236	1.6	15
69	Preparation of Nanocrystalline Silicon by Pulsed Plasma Processing. <i>Materials Research Society Symposia Proceedings</i> , 1994 , 358, 721		27
68	Preparation of Nanocrystalline Silicon by Digital Chemical Vapor Deposition. <i>Springer Series in Materials Science</i> , 1994 , 248-253	0.9	1
67	Low-Temperature Chemical Vapor Deposition of RBa2Cu3OX (R=Y, Pr) Ultra Thin Films 1994 , 921-924		
66	The role of hydrogen radicals in nucleation and growth of nanocrystalline silicon. <i>Journal of Non-Crystalline Solids</i> , 1993 , 164-166, 993-996	3.9	21
65	In SituOptical Monitoring of Two-Dimensional Crystal Growth in Layer-by-Layer Chemical Vapor Deposition of YBa2Cu3Ox. <i>Japanese Journal of Applied Physics</i> , 1993 , 32, L683-L686	1.4	9
64	Proposal of Trench-Oxide Metal-Oxide-Semiconductor Structure and Computer Simulation of Silicon Quantum-Wire Characteristics. <i>Japanese Journal of Applied Physics</i> , 1993 , 32, 6213-6217	1.4	4
63	Frequency effects in processing plasmas of the VHF band. <i>Plasma Sources Science and Technology</i> , 1993 , 2, 26-29	3.5	42
62	High Quality YBaCuO Thin Film Growth by Low-Temperature Metalorganic Chemical Vapor Deposition Using Nitrous Oxide. <i>Materials Research Society Symposia Proceedings</i> , 1993 , 335, 291		1
61	Self-limiting adsorption and in situ optical monitoring for atomic layer epitaxy of oxide superconductors layer epitaxy of oxide superconductors. <i>Thin Solid Films</i> , 1993 , 225, 284-287	2.2	12

60 In Situ Optical Diagnostics for Layer-by-Layer CVD of YBaCuO Films **1993**, 841-844

59	In SituMonitoring of Optical Reflectance Oscillation in Layer-by-Layer Chemical Vapor Deposition of Oxide Superconductor Films. <i>Japanese Journal of Applied Physics</i> , 1992 , 31, L1243-L1245	1.4	19
58	Growth Mechanism of Microcrystalline Silicon Prepared by Alternating Deposition of Amorphous Silicon and Hydrogen Radical Annealing. <i>Japanese Journal of Applied Physics</i> , 1992 , 31, L1388-L1391	1.4	13
57	Preparation of Highly Oriented Copper Films by Photo-Assisted Chemical Vapor Deposition Using Diketonate Complex. <i>Japanese Journal of Applied Physics</i> , 1992 , 31, L588-L590	1.4	12
56	Preparation of YBa2Cu3OxThin Films by Layer-by-Layer Metalorganic Chemical Vapor Deposition. <i>Japanese Journal of Applied Physics</i> , 1992 , 31, L787-L789	1.4	17
55	Preparation and Characterization of YBaCuO Superconducting Films by Low-Temperature Chemical Vapor Deposition Using 即iketonate Complex and N2O. <i>Japanese Journal of Applied Physics</i> , 1992 , 31, 3839-3843	1.4	14
54	Preparation of Microcrystalline Silicon Films by Very-High-Frequency Digital Chemical Vapor Deposition. <i>Japanese Journal of Applied Physics</i> , 1992 , 31, 1948-1952	1.4	41
53	Role of Hydrogen Radical Treatment in Nucleation of Nanocrystalline Silicon. <i>Japanese Journal of Applied Physics</i> , 1992 , 31, L1443-L1445	1.4	18
52	Separation of Nucleation and Growth Processes of Nanocrystalline Silicon by Hydrogen Radical Treatment of Hydrogenated Amorphous Silicon. <i>Materials Research Society Symposia Proceedings</i> , 1992 , 283, 519		5
51	Selflimiting adsorption of precursors for chemical vapor deposition of oxide superconductors. <i>Physica C: Superconductivity and Its Applications</i> , 1991 , 185-189, 2001-2002	1.3	3
50	Low-temperature chemical vapor deposition of YBa2Cu3Ox films. <i>Physica C: Superconductivity and Its Applications</i> , 1991 , 185-189, 2103-2104	1.3	2
49	Mercury-sensitized photo-induced chemical vapor deposition of YBa2Cu3Ox films. <i>Physica C:</i> Superconductivity and Its Applications, 1991 , 190, 151-153	1.3	5
48	Fabrication of MOS Nanostructure by Employing Electron Beam Lithography and Anisotropic Wet Etching of Silicon. <i>Japanese Journal of Applied Physics</i> , 1991 , 30, L415-L417	1.4	5
47	Nanometer Patterning by Electron Beam Lithography Using an Amorphous Carbon Film as an Intermediate Layer. <i>Japanese Journal of Applied Physics</i> , 1991 , 30, 890-891	1.4	
46	High quality a-Si:H films and interfaces prepared by VHF plasma CVD. <i>Journal of Non-Crystalline Solids</i> , 1991 , 137-138, 677-680	3.9	19
45	Properties of Metalorganic Precursors for Chemical Vapor Deposition of Oxide Superconductors. Japanese Journal of Applied Physics, 1990 , 29, L1072-L1074	1.4	27
44	Diagnostic Study of VHF Plasma and Deposition of Hydrogenated Amorphous Silicon Films. Japanese Journal of Applied Physics, 1990 , 29, 1889-1895	1.4	71
43	Heteroepitaxial growth of HgTe on InSb at 200 LC by metalorganic chemical vapor deposition using ditertiarybutyltelluride. <i>Journal of Applied Physics</i> , 1989 , 65, 1808-1810	2.5	2

42	Generation of Electron Cyclotron Resonance Plasma in the VHF Band. <i>Japanese Journal of Applied Physics</i> , 1989 , 28, L1860-L1862	1.4	8
41	Epitaxial Growth of YBaCuO Films on Sapphire at 500°C by Metalorganie Chemical Vapor Deposition. <i>Japanese Journal of Applied Physics</i> , 1989 , 28, L427-L429	1.4	27
40	Amorphous lilicon thin film transistors and their integrated circuits. <i>Electronics and Communications in Japan</i> , 1989 , 72, 48-60		
39	Construction of amorphous silicon ISFET. Sensors and Actuators, 1989, 16, 55-65		25
38	. IEEE Transactions on Electron Devices, 1988, 35, 2448	2.9	
37	. IEEE Transactions on Electron Devices, 1988 , 35, 1664-1671	2.9	
36	. IEEE Transactions on Electron Devices, 1988, 35, 919-922	2.9	10
35	Electrical properties of a CdTe/InSb hetero metal-insulator-semiconductor structure. <i>Applied Physics Letters</i> , 1988 , 52, 1306-1307	3.4	9
34	Numerical Analysis of the Dynamic Characteristics of Amorphous Silicon Thin-Film Transistors. Japanese Journal of Applied Physics, 1988 , 27, L919-L921	1.4	5
33	Evaluation of Deep States in Amorphous-Silicon/Silicon-Nitride System from Charge-Coupled Device Characteristics. <i>Japanese Journal of Applied Physics</i> , 1988 , 27, L1337-L1339	1.4	2
32	Fabrication of Nanostructure by Anisotropic Wet Etching of Silicon. <i>Japanese Journal of Applied Physics</i> , 1988 , 27, L1778-L1779	1.4	11
31	Preparation of a-Si:H Films by VHF Plasma CVD. <i>Materials Research Society Symposia Proceedings</i> , 1988 , 118, 117		34
30	Normal-Pressure and Low-Temperature Thermal Oxidation of Silicon. <i>Japanese Journal of Applied Physics</i> , 1987 , 26, 1907-1911	1.4	5
29	Preparation Method and Optoelectrical Properties of a-Se/CdxSe1-xMultilayer Films. <i>Japanese Journal of Applied Physics</i> , 1987 , 26, 991-995	1.4	14
28	Preparation of Polycrystalline Silicon by Hydrogen-Radical-Enhanced Chemical Vapor Deposition. <i>Japanese Journal of Applied Physics</i> , 1987 , 26, L10-L13	1.4	70
27	Design of Band Potential with a-SixGe1-x:H(F) Alloys. <i>Japanese Journal of Applied Physics</i> , 1987 , 26, L1	69±1_472	2 13
26	Hole Transport in Silicon Thin Films with Variable Hydrogen Content. <i>Japanese Journal of Applied Physics</i> , 1987 , 26, L276-L279	1.4	14
25	Growth of Amorphous and Crystalline Silicon by HR-CVD (Hydrogen Radical Enhanced CVD). Materials Research Society Symposia Proceedings, 1987, 95, 225		56

24	Preparation of a-Si and its Related Materials by Hydrogen Radical Enhanced CVD 1987 , 435-446		6
23	Material Design by Structural Modulation of Amorphous Semiconductors 1987 , 563-575		2
22	Reactive Deposition of a-Silicon and Si-Based Alloys. <i>Materials Research Society Symposia Proceedings</i> , 1986 , 70, 11		6
21	Design of multiple layered a-Si:H(F)/a-SiGex:H(F) films for enhancement in photoresponse in the near-infrared spectrum. <i>Applied Physics A: Solids and Surfaces</i> , 1986 , 41, 259-265		14
20	Hole Transport in a-Si:H(F) Prepared by Hydrogen-Radical-Assisted Chemical Vapor Deposition. <i>Japanese Journal of Applied Physics</i> , 1986 , 25, 1783-1787	1.4	11
19	Electronic States In Glow-Discharge a-SiGex:H:(F) Alloys. <i>Japanese Journal of Applied Physics</i> , 1986 , 25, 49-52	1.4	15
18	Preparation of Highly Photoconductive a-SiGexfrom Fluorides by Controlling Reactions with Atomic Hydrogen. <i>Japanese Journal of Applied Physics</i> , 1986 , 25, L540-L543	1.4	17
17	The Role of Hydrogen Radicals in the Growth of a-Si and Related Alloys. <i>Japanese Journal of Applied Physics</i> , 1986 , 25, L188-L190	1.4	34
16	Designing New Materials with Amorphous Semiconductors Structure and Electrical Properties of Multiply Stacked a-Si/a-SiGexLayers <i>Japanese Journal of Applied Physics</i> , 1986 , 25, L537-L539	1.4	12
15	Hydrogen radical assisted chemical vapor deposition of ZnSe. <i>Applied Physics Letters</i> , 1986 , 48, 33-35	3.4	27
14	Highly Oriented ZnO Films Prepared by MOCVD from Diethylzinc and Alcohols. <i>Japanese Journal of Applied Physics</i> , 1985 , 24, 1607-1610	1.4	78
13	Properties of a-Si based alloys prepared from fluorides and hydrogen. <i>Journal of Non-Crystalline Solids</i> , 1985 , 77-78, 877-880	3.9	29
12	Transient photoluminescence and photo-induced optical absorption in polymeric and crystalline sulphur The Philosophical Magazine: Physics of Condensed Matter B, Statistical Mechanics, Electronic, Optical and Magnetic Properties, 1984, 50, 373-377		6
11	The residual voltage in fast electrophotography of a-SiHx. <i>Solar Energy Materials and Solar Cells</i> , 1982 , 8, 123-128		6
10	The role of the blocking structure in hydrogenated amorphous silicon vidicon targets. <i>Journal of Applied Physics</i> , 1981 , 52, 7275-7280	2.5	13
9	Electrophotographic studies of glow-discharge amorphous silicon. <i>The Philosophical Magazine:</i> Physics of Condensed Matter B, Statistical Mechanics, Electronic, Optical and Magnetic Properties, 1981, 43, 1079-1089		18
8	Vidicon target of a p-i-n structure using a-Si:H. <i>Journal of Applied Physics</i> , 1980 , 51, 6422-6423	2.5	12
7	Preparation and characterization of low-voltage cathodoluminescent ZnS. <i>Journal of Luminescence</i> , 1979 , 18-19, 365-368	3.8	7

6	A new emission band in self-activated ZnS. Journal of Luminescence, 1979, 18-19, 829-832	3.8	45
5	Low-voltage cathodoluminescence of ZnS single crystals. <i>Journal of Luminescence</i> , 1978 , 16, 323-330	3.8	9
4	Preparation and characterization of low-resistivity ZnS for blue LEDQ. <i>IEEE Transactions on Electron Devices</i> , 1977 , 24, 956-958	2.9	22
3	Blue emission from forward-biased ZnS diodes. <i>Journal of Luminescence</i> , 1976 , 12-13, 923-927	3.8	20
2	ZnS blue-light-emitting diodes with an external quantum efficiency of 5🗓0🖟. <i>Applied Physics Letters</i> , 1975 , 27, 697-699	3.4	71
1	Observation of Quantum Level Spectrum for Silicon Double Single-Electron Transistors. <i>Applied Physics Express</i> ,1, 051401	2.4	1